

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/629,040 <b>Examiner</b> John M. Frink	<b>Applicant(s)/Patent under Reexamination</b> MAYO ET AL. <b>Art Unit</b> 2142	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner	DATE	EXMR	
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			